

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/699,163	<b>Applicant(s)/Patent under Reexamination</b>  MASHIYAMA ET AL.
	<b>Examiner</b>  Hae M. Hyeon	<b>Art Unit</b>  2839

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
439	608	2/05	hawth
439	108	↓	↓